

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2410		PRIORITY SERIAL NO. 10/017,557	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				PRIORITY FILING DATE 12/14/2001		PRIORITY GROUP 2823	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclasses	Filing Date if Appropriate
BKS ↓	AA	6,104,053	8/00	Nagai			
	AB	5,998,251	12/99	Wu et al.			
	AC	5,414,655	5/95	Ozaki et al.			
	AD	5,981,369	11/99	Yoshida et al.			
	AE	6,281,540	8/01	Aoki			
	AF	6,130,449	10/00	Matsuoka			
	AG	4,907,046	3/90	Ohji et al.			
	AH	6,107,139	8/00	Tu et al.			
	AI	6,333,225	12/01	Schuegraf et al.			
	AJ						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclasses	Translation
BKS	AK	0 889 519 A2		EPO			Yes    No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
BKS	AM		Kwon, K., et al., <i>Ta2O5 Capacitors for 1 Gbit DRAM and Beyond</i> , 1994 IEEE, pp. 34.2.1-34.2.4				
BKS	AN		Sun, S., et al., <i>A New CVD Tungsten Nitride Diffusion Barrier for Cu Interconnection</i> , 1996 Symposium on VLSI Technology Digest of Technical Papers, pp. 46-47				
	AO						
	AP						
EXAMINER				DATE CONSIDERED <u>4/18/04</u>			
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